

PTO-1449  Information Disclosure Citation in an Application		Application No. 09/864,714		Applicant(s) Ajit P. Paranjpe et al.	
Docket Number 021208.0238		Group Art Unit 2814		Filing Date May 23, 2001	

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 NOV 30 2005

U.S. PATENT DOCUMENTS						
	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	6174377	1/16/2001	Doering et al.	118	729	1/4/99
B.	5879459	3/09/1999	Gadgil et al.	118	715	8/29/97
C.	5916365	6/29/1999	Sherman	117	92	8/16/96
D.	6015590	1/18/2000	Suntola et al.	427	255.23	09/25/96
E.	6200893	3/13/2001	Sneh	438	685	3/11/99
F.	6342277	1/29/2002	Sherman	427	562	4/14/99
G.	2002/0041931	4/11/2002	Suntola et al.	427	255.28	5/14/01
H.	6387185	5/14/2002	Doering et al.	118	729	1/16/01
I.	6391785	5/21/2002	Satta et al.	438	704	8/23/00
J.	6416577	7/9/2002	Suntola et al.	117	88	06/07/00
K.	2002/0106846	8/8/2002	Seutter et al.	438	200	2/2/01
L.	2002/0108570	8/15/2002	Lindfors	118	715	4/16/01
M.	6447607	9/10/2002	Soininen et al.	117	200	12/27/00
N.	6451119*	9/17/2002	Sneh et al.	118	715	11/29/00
O.	6451695	9/17/2002	Sneh	438	685	12/22/00
P.	6464779	10/15/2002	Powell et al.	117	89	1/19/01
Q.	6475910	11/5/2002	Sneh	438	685	9/22/00
R.	6475276	11/5/2002	Elers et al.	117	84	10/13/00
S.	6482262	11/19/2002	Elers et al.	117	84	10/13/00
T.	6482740	11/19/2002	Soininen et al.	438	686	5/15/01

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	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
U.	62221102	09/29/1987	JP (with English abstract)	H01F	41/14		X
V.	WO 00/38191	06/29/2000	PCT	G11C	11/15	X	

NON-PATENT DOCUMENTS - DOCUMENT (Including Author, Title, Source, and Pertinent Pages)		
W.	Addison, C.C. et al. "The Vapour Pressure of Anhydrous Copper Nitrate, and its Molecular Weight in the Vapour State", <i>J. Chem. Soc.</i> , pp. 3099-3106	1958
X.	Akerman, J.J et al., "Identifying Tunneling in Ferromagnetic-Insulator-Ferromagnetic Thin Film Structures", World-wide web, physics.ucsd.edu/ksgrp/Tunneling.html, pp. 1-6,	Printed 02/04/2002
Y.	Bobo, J.F. et al., "Spin-dependent Tunneling Junctions with Hard Magnetic layer Pinning", <i>Journal of Applied Physics</i> , vol. 83, No. 11, pp. 6685-6687	1998
Z.	Daughton, J.M., World-wide web nve.com/otherbiz/mram2.pdf, "Advanced MRAM Concepts", pp. 1-6	02/07/2001

EXAMINER	DATE CONSIDERED
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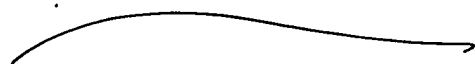
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		U.S. PATENT DOCUMENTS			

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
21	A.	2002/0187084	12/12/2002	Lindfors et al.	422	177	7/24/02
	B.	6503330	1/7/2003	Sneh et al.	118	715	12/22/99
	C.	6506352	1/14/2003	Lindfors et al.	423	240	7/20/00
	D.	6511539	1/28/2003	Raaijmakers	117	102	9/8/99
	E.	6524952	2/25/2003	Srinivas et al.	438	649	6/20/00
	F.	6540838	4/1/2003	Sneh et al.	118	715	6/28/02
	G.	6548424	4/15/2003	Putkonen	438	785	4/16/01
	H.	6551406	4/22/2003	Kilpi	118	728	12/27/00
	I.	6562140	5/13/2003	Bondestam et al.	118	715	5/10/00
	J.	2003/0098468	5/22/2003	Solinen et al.	438	200	11/19/02
	K.	6572705	6/3/2003	Suntola et al.	118	702	1/14/00
	L.	2003/0101927	6/5/2003	Raaijmakers	117	200	12/10/02
	M.	6578374	6/17/2003	Bondestam et al.	118	725	1/25/01
	N.	2003/0121469	7/3/2003	Lindfors et al.	117	105	10/11/02
	O.	6599572	7/29/2003	Saani et al.	427	249.18	1/18/01
	P.	2003/0140854	7/31/2003	Kilpi	118	715	2/13/03
	Q.	6602784	8/5/2003	Sneh	438	680	8/6/02
	R.	2003/0150385	8/14/2003	Bondestam et al.	118	722	3/6/03
	S.	6616986	9/9/2003	Sherman	427	562	10/9/01
	T.	6620723	9/16/2003	Byun et al.	438	627	6/27/00
51	U.	6627268	9/30/2003	Fair et al.	427	533	5/3/01

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22	V.	WO 02/09126	01/31/2002	PCT	H01F	10/32	X
22	W.	W 02/09158	01/31/2002	PCT	H01L	21/00	X

NON-PATENT DOCUMENTS - DOCUMENT (Including Author, Title, Source, and Pertinent Pages)			
53	X.	Fereday, R.J. et al., "Anhydrous Cobalt (III) Nitrate", <i>Chemical Communications</i> , pp. 271	1968
	Y.	Hsiao, R., "Fabrication of Magnetic Recording Heads and Dry Etching Head Materials", <i>IBM Journal of Research and Development</i> , vol. 43, (1/2):1999, pp. 89-102	1999
54	Z.	Imai, Takuji, World-wide web <a href="http://nikkeibp.asiabiztech.com/nea/200008/tech_108675.html">nikkeibp.asiabiztech.com/nea/200008/tech_108675.html</a> , "100 Gbit/Inch HDD Just Around the Corner", pp. 1-6	08/2000

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Application No.

Applicant(s)

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in an Application

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Ajit P. Paranjpe et al.

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		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
✓	A.	2003/0183171	10/2/2003	Sneh et al.	118	724	3/27/03
	B.	6630401	10/7/2003	Sneh	438	680	8/8/02
	C.	6630030	10/7/2003	Suntola et al.	118	728	1/4/00
	D.	6632279	10/14/2003	Ritola et al.	117	101	10/13/00
	E.	6635985	10/21/2003	Lee et al.	257	758	10/9/01
	F.	6638862	10/28/2003	Sneh	438	685	8/8/02
	G.	6638859	10/28/2003	Sneh et al.	438	680	9/27/02
	H.	6638810	10/28/2003	Bakil et al.	438	240	11/5/01
	I.	6652924	11/25/2003	Sherman	427	576	5/24/01
	J.	6660126	12/9/2003	Nguyen et al.	156	345.34	3/2/01
	K.	6664192	12/18/2003	Satta et al.	438	704	4/15/02
	L.	2004/0005753	1/8/2004	Kostamo et al.	438	222	3/20/03
	M.	2004/0007171	1/15/2004	Ritola et al.	117	89	7/10/03
	N.	6679951	1/20/2004	Soininen et al.	148	240	11/13/01
	O.	6689210	2/10/2004	Soininen et al.	117	89	7/24/02
	P.	6720260	4/13/2004	Fair et al.	438	680	6/20/03
	Q.	2004/0076837	4/22/2004	Hein et al.	428	446	10/22/02
	R.	2004/0076751	4/22/2004	Sherman	427	255.34	10/10/03
	S.	6727169	4/27/2004	Raaijmakers et al.	438	622	8/23/00
	T.	2004/0083949	5/6/2004	Sherman	117	84	10/22/03
	U.	6734020	5/11/2004	Lu et al.	436	55	3/7/01
	V.	2004/0121616	6/24/2004	Satta et al.	438	778	12/8/03
✓	W.	6759081	7/6/2004	Huganen et al.	427	58	4/30/02
✓	X.	2004/0130029	7/8/2004	Raaijmakers et al.	257	758	12/15/03

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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
✓	Y.	WO 01/88972	11/22/2001	PCT	H01L	21/321	X	

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✓	Z.	Nilsen, O et al, "Thin Film Deposition of lanthanum Manganite Perovskite by the ALE Process", <i>Journal of Materials Chemistry</i> , vol. 9, pp. 1781-1784.					1999
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<input checked="" type="checkbox"/>	A.	6764546	7/20/2004	Raaijmakers	117	93	12/10/02
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<input type="checkbox"/>	C.	6777353	8/17/2004	Putkonen	438	785	4/8/03
<input type="checkbox"/>	D.	2004/0161636	8/19/2004	Hujanen et al.	428	692	2/17/04
<input type="checkbox"/>	E.	6794287	9/21/2004	Saanila et al.	438	674	3/20/03
<input type="checkbox"/>	F.	6800173	10/5/2004	Chiang et al.	156	345.33	7/9/01
<input type="checkbox"/>	G.	6800552	10/5/2004	Elers et al.	438	680	9/17/02
<input type="checkbox"/>	H.	2004/0202786	10/14/2004	Wongsenakhum et al.	427	250	3/31/04
<input type="checkbox"/>	I.	6811814	11/2/2004	Chen et al.	427	248.1	1/16/02
<input type="checkbox"/>	J.	6818067	11/18/2004	Doering et al.	118	715	4/15/02
<input checked="" type="checkbox"/>	K.	6821889	11/23/2004	Elers et al.	438	680	7/30/02

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<input checked="" type="checkbox"/>	M.	Pakrad, C.D., "Pure Tech: Growth of MR/GMR Head Materials," World-wide web, puretechinc.com/tech_papers/tech_papers-4.htm, pp. 1-2	1999
<input type="checkbox"/>	N.	Riihela et al., "Low Temperature Deposition of AlN Films by an Alternate Syppy of Trimethyl Aluminum and Ammonia" Chemical Vapor Deposition, 2 (6): pp. 277-283.	1996
<input type="checkbox"/>	O.	Suntola, Tuomo; Handbook of Crystal Growth, vol. 3, Thin Films and Epitaxy, Part B: Growth Mechanisms and Dynamics, Chapter 14, pp. 601-663, Hurle, ed. Elsevier Science B.V.	1994
<input type="checkbox"/>	P.	Ritala et al., "Atomic Layer Epitaxy-a Valuable Tool for Nanotechnology?" Nanotechnology vol. 10, pages 19-24	1999
<input type="checkbox"/>	Q.	Wang, Shan X., "Advanced Materials for Extremely High Density Magnetic Recording Heads," Department of Electrical Engineering, Stanford University, Stanford, CA 94305-4045, presentation.	no date available
<input type="checkbox"/>	R.	World-wide web, megahaus.com/tech/westerndigital/shitepapers/gmr_wp.shtml, "GMR Head Technology: Increased Areal Density and Improved Performance Areal Density," pp. 1-4.	02/2000
<input type="checkbox"/>	S.	World-wide web, semiconductor.net/semiconductor/issues/issues/1998/feb98/docs/emerging.asp, "GMR Read-Write Heads Yield Data Storage Record," pp. 1-2.	02/1998
<input type="checkbox"/>	T.	World-wide web, stoner.leeds.ac.uk/research/gmr.htm, "Giant Magnetoresistance (GMR) Heads", pp. 1-6.	Printed 02/04/2002
<input type="checkbox"/>	U.	World-wide web, pcguide.com/ref/hdd/op/heads/techGMR-c.html, "Giant Magnetoresistive (GMR) Heads", pp. 1-4.	Printed 12/18/2004
<input type="checkbox"/>	A.	Utrianen, et al., "Studies of Metallic Film Growth in an Atomic Layer Epitaxy reactor Using M(acac) <sub>2</sub> (M=Ni, Cu, Pt) Precursors", Applied Surface Science, vol. 157, pp. 151-158.	2000
<input checked="" type="checkbox"/>	V.	Ueno et al., "Cleaning of CHF <sub>3</sub> , plasma-etched SiO <sub>2</sub> /SiN/Cu via Structures Using a Hydrogen Plasma, an Oxygen Plasma and Hexafluoroacetylacetone Vapors," J. Vac. Sci. Technology B, vol. 16, No. 6, pp. 2986-2995.	Nov/Dec. 1998

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<b>U.S. PATENT DOCUMENTS</b>							
		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
9	A.	5647911	07/15/97	Vanell et al.	118	715	12/14/93
	B.	5711811	01/27/98	Suntola et al.	118	711	11/28/95
	C.	5916369	06/29/99	Anderson et al.	118	715	06/07/95
	D.	2003/0003635 A1	01/02/03	Paranjpe et al.	438	149	05/23/01
	E.						
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	G.						
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	J.						
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	K.						
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9	L.	Omstead, Thomas, et al.; "Filling High-AR Structures Using Pulsed Nucleation Layer Deposition", Solid State Technology, Vol. 45, pp. 51-56.					09/2002
	M.						
	N.						
	O.						
	P.						
	Q.						
	R.						
	S.						
	T.						
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	V.						
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